

BIG IMPROVEMENTS TO HELP YOU SPOT SMALL DIFFERENCES

Details matter. Minuscule changes in your sample material can result in big differences in a finished product.

That's why the **LS 13 320 XR laser diffraction particle size distribution analyzer** uses 132 detectors to provide higher resolution for more accurate results, together with an expanded measurement range from 10 nm - 3,500 μm .

DETAILS THAT MATTER

- 1 Expanded measurement range: 10 nm - 3,500 μm**
Provides real (not extrapolated) analytical data down to 10 nm, and high-resolution measurements up to 3,500 μm
- 2 Enhanced PIDS technology: Polarization Intensity Differential Scattering**
Enables more precise raw data detection and increased detector sensitivity of vertical and horizontal polarized scattered light for sub- μm particle size analysis - a measurement quality previously unavailable
- 3 Advanced automodality**
No knowledge about particle size distribution (e.g., multiple fractions, narrow distribution) needed prior to measurement in order to obtain a correct result
- 4 Optimized, intuitive software**
 - Requires 2 clicks from Start Measurement to result
 - Includes an integrated optical constants database
 - Helpful user diagnostics keep you informed
 - Streamlines workflows to save time

DATA INTEGRITY & COMPLIANCE

The FDA's Electronic Records and Electronic Signatures Rule (21 CFR Part 11) defines requirements for submitting documentation in electronic form. Choosing the software's highest security option enables you to configure the system to automatically support 21 CFR Part 11 compliance via:

- Secure user sign-on
- User-level permissions
- Audit trail
- Error log files
- Administrative configuration tools

VALIDATION

This is a must for Good Manufacturing Practices and other regulatory requirements. Therefore the LS 13 320 XR analyzer supports GMP with specific tools for Installation Qualification (IQ) and Operational Qualification (OQ).



**DIFFERENCES YOU
CAN MEASURE**



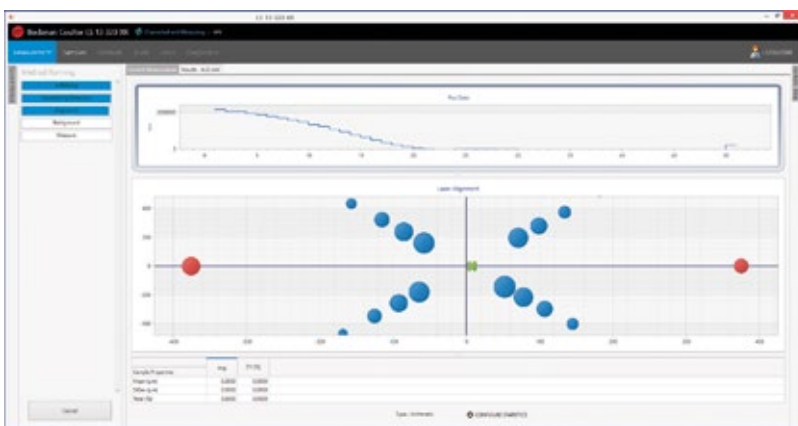
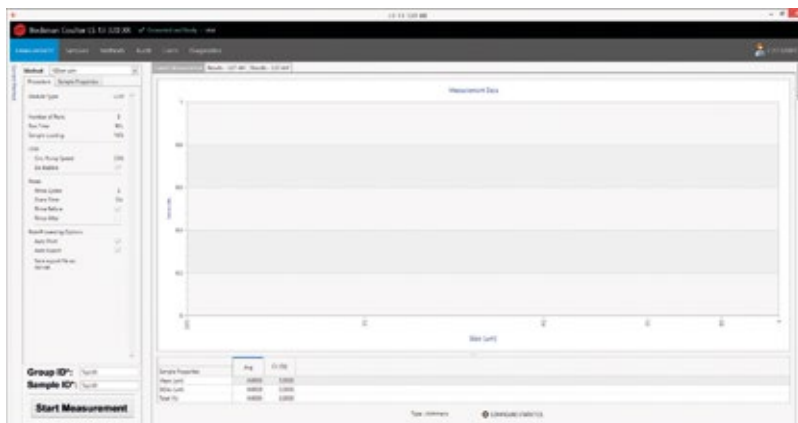
EASY-TO-USE SOFTWARE SIMPLIFIES YOUR DAILY WORKLOAD

PARTICLE SIZE ANALYSIS IS MORE EFFICIENT THAN EVER BEFORE

You will appreciate the differences in easy-to-use LS 13 320 XR software because functionality is more intuitive, and you don't need extensive operator knowledge to get accurate data.

START YOUR MEASUREMENT

As soon as a method is set up in the LS 13 320 XR software, a measurement can be started with 2 clicks. Choose a pre-configured method, define your Test-ID and Group-ID and hit Start Measurement.



INSTRUMENT SELF-CHECK RESULTS

The instrument keeps you informed during sampling with helpful self-check diagnostics.

PIDS TECHNOLOGY

Polarization Intensity Differential Scattering (PIDS) technology enables not only direct detection of particles as small as 10 nm, but also direct detection of multimodal fractions in the sub- μm range.





PREPARATION

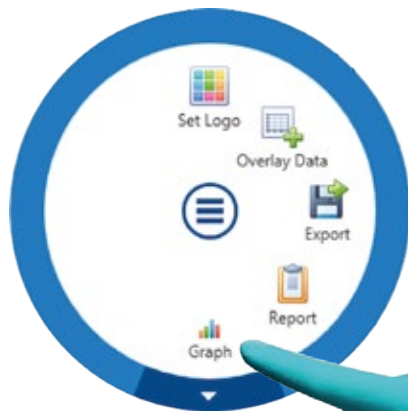
MEASUREMENT

RESULTS

1st Run	2nd Run	3rd Run
Carbon	Carbon	Carbon
14.84	15.04	15.20
69.76	71.29	70.73
181.5	219.6	201.5
108.0	136.4	118
100.0	100.0	100

AUTOMATIC PASS/FAIL CONTROL FOR IMMEDIATE QC

For immediate pass/fail checks of sample specifications, LS 13 320 XR software automatically highlights results in green or red if the measurement is within or outside required specifications. This enables fast quality control responses by experienced and inexperienced operators alike.



NAVIGATION WHEEL

Data presentation and export handling with just 1 click.

